

P-Ch 60V Fast Switching MOSFETs

Features:

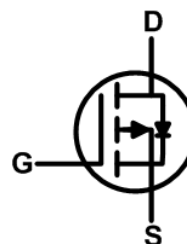
- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology



SOT223 Pin Configuration

Description:

The KWL6107 is the high cell density trenched P-ch MOSFETs, which provides excellent $R_{DS(on)}$ and efficiency for most of the small power switching and load switch applications. The KWL6107 meets the RoHS and Green Product requirement with full function reliability approved.



Product Summary

BVDSS	$R_{DS(on)}$	ID
-60V	180mΩ	-2.3A

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_A=25^\circ\text{C}$	Continuous Drain Current, V_{GS} @ -10V ¹	-2.3	A
$I_D@T_A=70^\circ\text{C}$	Continuous Drain Current, V_{GS} @ -10V ¹	-1.8	A
I_{DM}	Pulsed Drain Current ²	-12	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation ³	1.5	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	---	85	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	48	$^\circ\text{C/W}$

Electrical Characteristics ($T_J=25\text{ }^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V$, $I_D=-250\mu A$	-60	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $I_D=-1mA$	---	-0.038	---	V/ $^{\circ}\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=-10V$, $I_D=-2A$	---	140	180	$m\Omega$
		$V_{GS}=-5V$, $I_D=-1.5A$	---	200	260	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=-250\mu A$	-1.5	-2.0	-2.5	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.92	---	mV/ $^{\circ}\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=-48V$, $V_{GS}=0V$, $T_J=25^{\circ}\text{C}$	---	---	1	μA
		$V_{DS}=-48V$, $V_{GS}=0V$, $T_J=55^{\circ}\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=-5V$, $I_D=-2A$	---	5.3	---	S
Q_g	Total Gate Charge (-10V)	$V_{DS}=-48V$, $V_{GS}=-10V$, $I_D=-2A$	---	8.3	11.6	nC
Q_{gs}	Gate-Source Charge		---	1.8	2.52	
Q_{gd}	Gate-Drain Charge		---	1.6	2.25	
$T_{d(on)}$	Turn-On Delay Time	$V_{DS}=-30V$, $V_{GS}=-10V$, $R_G=3.3\Omega$, $I_D=-2A$	---	4.1	8.2	ns
T_r	Rise Time		---	21	38	
$T_{d(off)}$	Turn-Off Delay Time		---	20.3	40.6	
T_f	Fall Time	$V_{DS}=-15V$, $V_{GS}=0V$, $f=1MHz$	---	21	42	pF
C_{iss}	Input Capacitance		---	428	600	
C_{oss}	Output Capacitance		---	39	55	
C_{rss}	Reverse Transfer Capacitance		---	26	36.4	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current ^{1,4}	$V_G=V_D=0V$, Force Current	---	---	-2.3	A
I_{SM}	Pulsed Source Current ^{2,4}		---	---	-12	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V$, $I_S=-1A$, $T_J=25^{\circ}\text{C}$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The power dissipation is limited by 150°C junction temperature
- 4.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

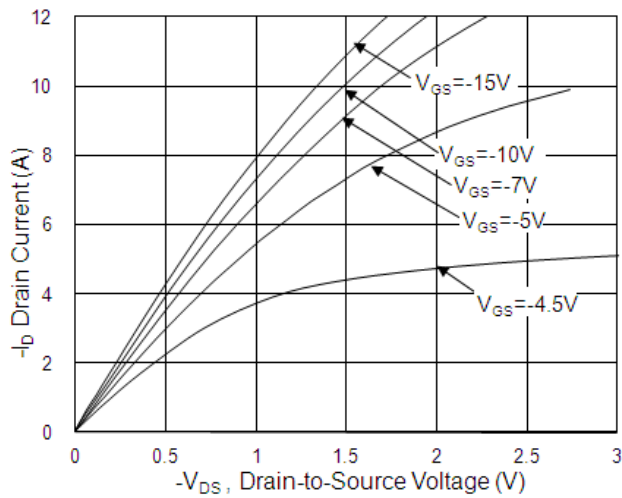


Fig.1 Typical Output Characteristics

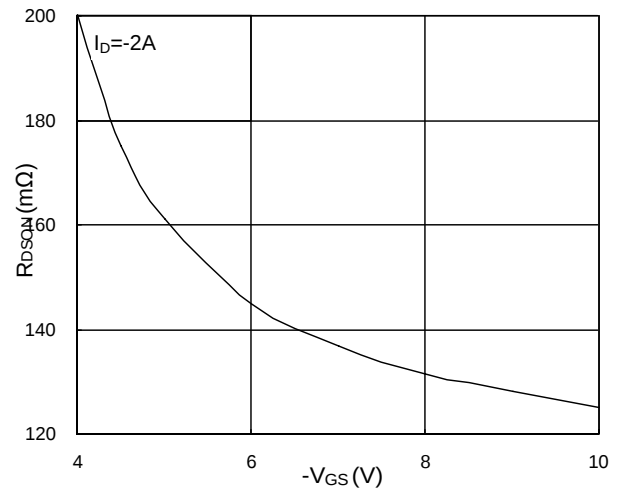


Fig.2 On-Resistance vs. Gate-Source Voltage

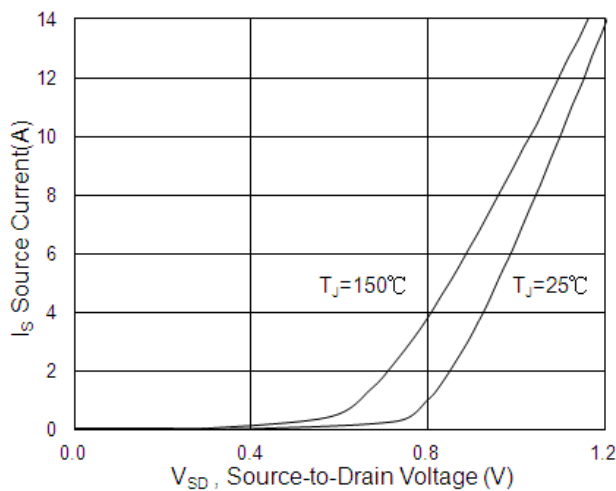


Fig.3 Forward Characteristics Of Reverse

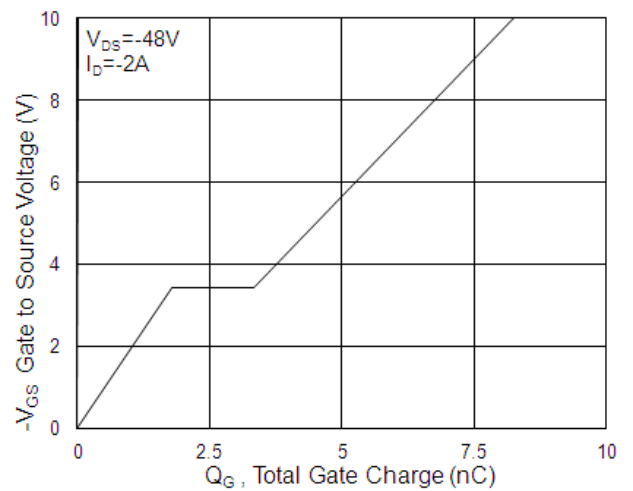


Fig.4 Gate-Charge Characteristics

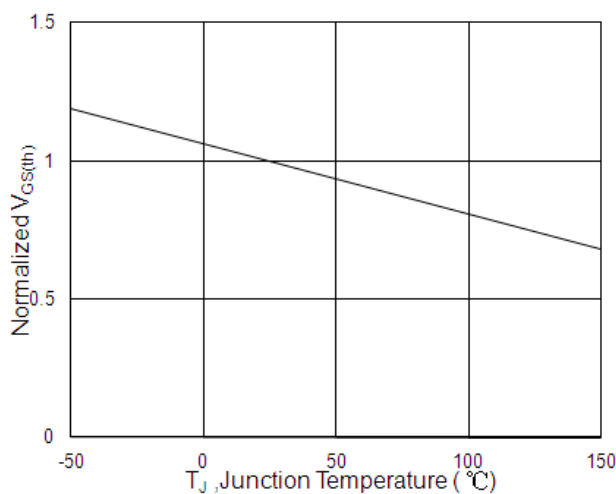


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

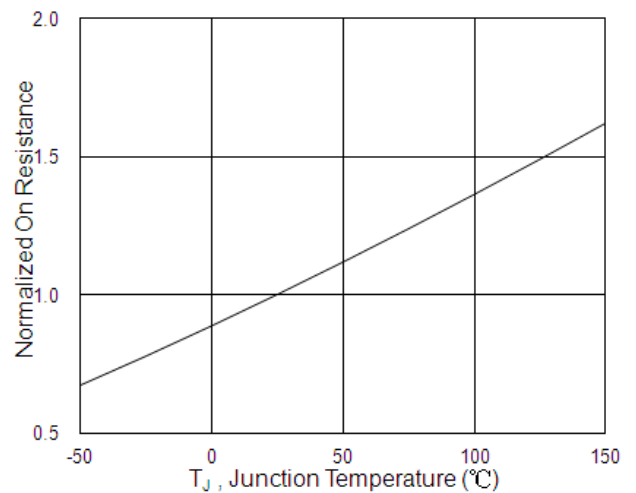


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

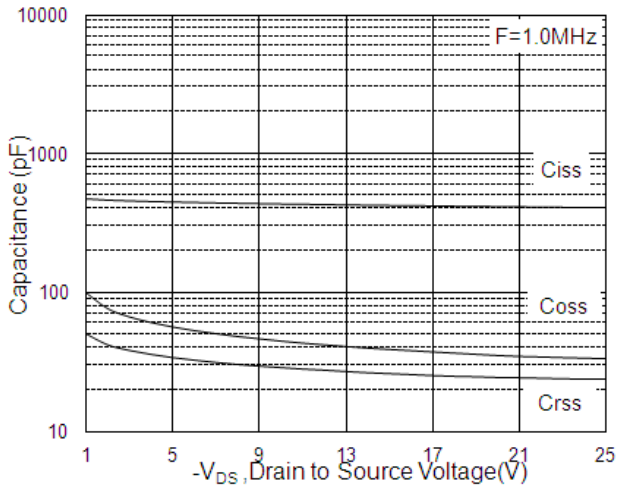


Fig.7 Capacitance

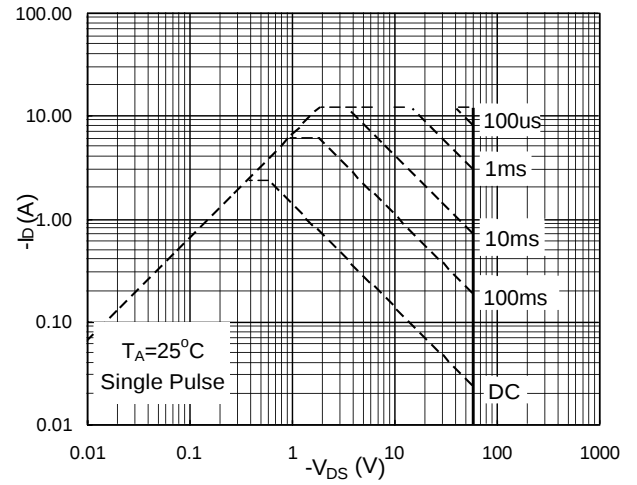


Fig.8 Safe Operating Area

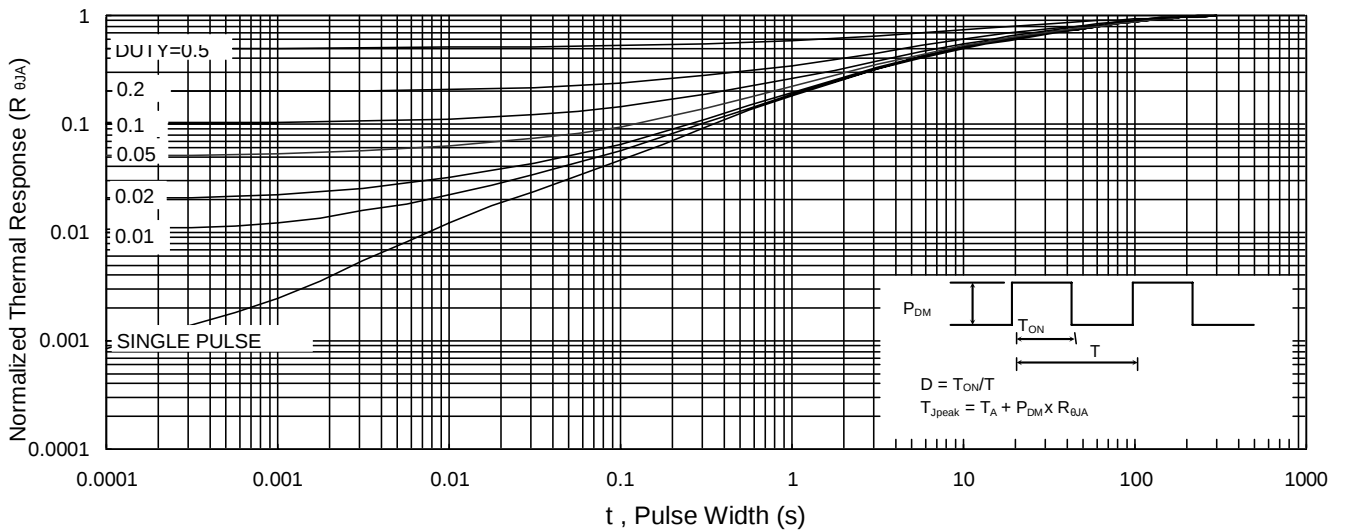


Fig.9 Normalized Maximum Transient Thermal Impedance

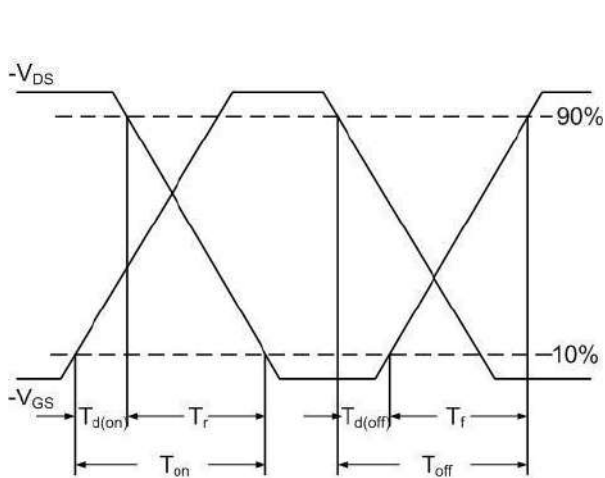


Fig.10 Switching time waveform

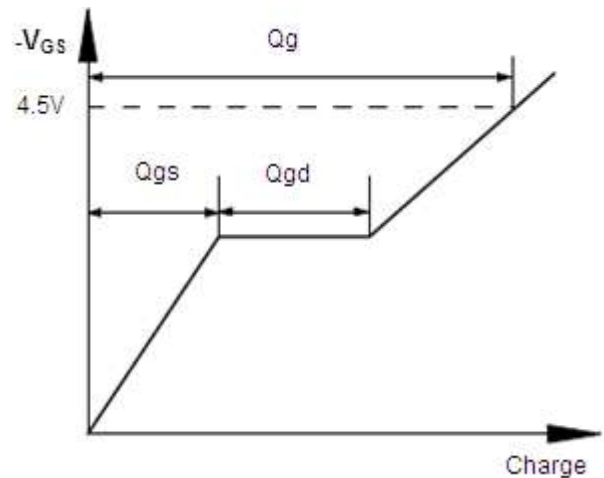


Fig.11 Gate Charge waveform